



Electronics Destructive Physical Analysis (DPA) Transistor



Reference Mil-Std-1580C

Trans Metal Can

- 21.1.1.1 External Visual (3 Samples)
 - 21.1.1.2 External Prohibited Materials (1 Sample) XRF or SEM/EDX
 - 21.1.1.3 Hermeticity (not available at this location)
 - 21.1.1.4 Radiography (3 Samples)
 - 21.1.1.5 PIND (not available at this location)
 - 21.1.1.6 RGA (not available at this location)
 - 21.1.1.7 Delidding (3 Samples)
 - 21.1.1.8 Crimp Tubulation Inspection (Pull) and Cross Section (1 Sample If applicable)
 - 21.1.1.9 Internal Visual (3 Samples)
 - 21.1.1.10 Internal Prohibited Materials (1 Sample) XRF or SEM/EDX
 - 21.1.1.11 Bond Pull (3 Samples)
 - 21.1.1.12 SEM (2 Samples)
 - 21.1.1.13 Die Shear (2 Samples)
- Photo Documentation and Report

Trans Plastic Encapsulated **

- 21.1.1.1 External Visual (3 Samples)
 - 21.1.1.2 External Prohibited materials (1 Sample) XRF or SEM/EDX
 - 21.1.1.4 Radiography (3 Samples)
 - 21.1.1.7 Chemical Decapsulation (3 Samples)
 - 21.1.1.9 Internal Visual (3 Samples)
 - 21.1.1.10 Internal Prohibited Materials (1 Sample) XRF or SEM/EDX
 - 21.1.1.11 Bond Pull (3 Samples)
 - 21.1.1.12 SEM (2 Samples)
 - 21.1.1.13 Die Shear (2 Samples)
- Photo Documentation and Report

** There is no specific requirements for Plastic Encapsulated Transistors (PETs)

For pricing, contact Jeff Jacques
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